Electronic Supplementary Material (ESI) for Journal of Materials Chemistry

Proximal oxidation as a director of self organization

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Supplementary electronic information

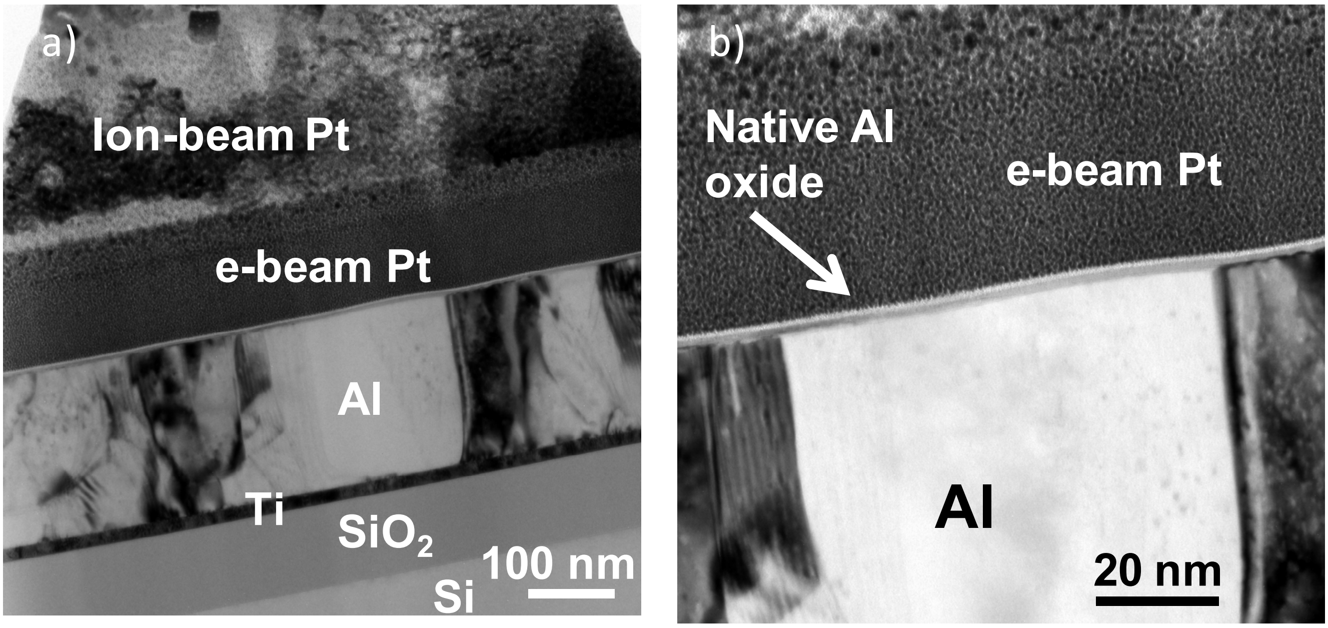

Fig 1 a) TEM cross sectional micrograph of the prepared substrate. From the bottom the different layers are highlighted: silicon substrate, silicon oxide layer, titanium adhesion layer, aluminium film and platinum deposited as protection layer for the FIB TEM lamella preparation. b) Magnified TEM micrograph showing the native oxide present on the surface.

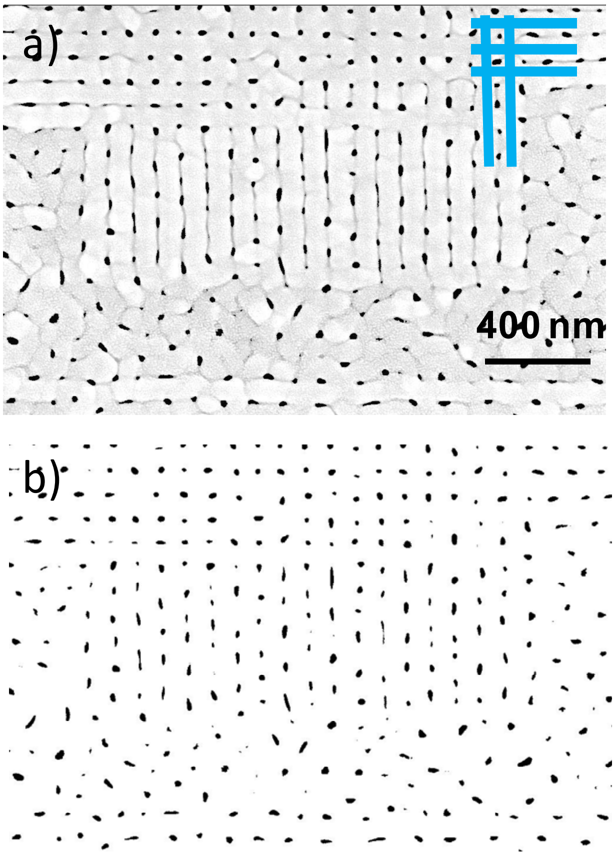

Fig. 2 a) Same picture as in figure 2b in the paper with an example of highlighted pre-oxidised lines. Pores nucleate in between the pre-patterned oxide lines where only native oxide is present. b) Same picture as in a) with only pore positions highlighted. A clear difference in pore ordering is observed between a random region (bottom) and the pre-patterned, order induced region (top).